

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

1 1. (currently amended): A measuring system for detecting defects of an
2 object having at least a first and a second layer, which system comprises at least one light source
3 arranged to illuminate the object with incident light, an a single two-dimensional imaging sensor
4 arranged to detect reflected light emanating from the object and to convert the detected light into
5 electrical charges, and[[,]] means for creating a representation of the object according to the
6 electrical charges, wherein the system comprises means for obtaining information from the
7 representation on of light scattered by entering the object and emerging from the object at a
8 different location from the entering location after being spread in the first layer and the second
9 layer of the object from the representation, and[[,]] means for comparing the information to
10 stored information in order to detect defects on the object.

1 2. (previously presented): A measuring system according to claim 1,
2 wherein the measuring system and/or the object is/are arranged to move in relation to one
3 another in a predefined direction of movement.

1 3. (previously presented): A measuring system according to claim 1,
2 wherein the incident light is arranged to have limited dispersion in a predefined direction.

1 4. (previously presented): A measuring system according to claim 3,
2 wherein the incident light is a linear light.

1 5. (previously presented): A measuring system according to claim 1,
2 wherein the system further comprises means for obtaining information on the geometric profile
3 of the object from the representation.

6. (previously presented): A measuring system according to claim 5, wherein the system comprises means for obtaining information on the geometric profile of the first layer of the object from the representation.

7. (previously presented): A measuring system according to claim 5, wherein the system comprises means for obtaining information on the geometric profile of the second layer of the object from the representation.

8. (previously presented): A measuring system according to claim 1, wherein the light source comprises a polarizer arranged to facilitate the distinction between light reflected on the object and scattered light in the object.

9. (previously presented): A measuring system according to claim 1, wherein the first layer consist of a transparent or semi-transparent material.

10. (previously presented): A measuring system according to claim 1, wherein the object is a package wrapped in a protective material.

11. (currently amended): A method for detecting defects of an object having at least a first and a second layer by means of a measuring system, in which method the object is illuminated by means of incident light, and light reflected and emanating from the object is detected by means of an a single two-dimensional imaging sensor in which the detected light is converted into electrical charges, according to which a representation of the object is created, wherein information is obtained from the representation of on light scattered by entering the object and emerging from the object at a different location from the entering location after being spread in the first layer and the second layer of the object is obtained from the representation and wherein the information is compared to stored information in order to detect defects on the object.

1 12. (previously presented): A method according to claim 11, wherein the
2 measuring system and/or the object is/are moved in relation to one another in a predefined
3 direction of movement.

1 13. (previously presented): A method according to claim 11, wherein also
2 information on the geometric profile of the object is obtained from the representation.

1 14. (previously presented): A method according to claim 13, wherein
2 information on the geometric profile of the first layer of the object is obtained from the
3 representation.

1 15. (previously presented): A method according to claim 13, wherein
2 information on the geometric profile of the second layer of the object is obtained from the
3 representation.

1 16. (previously presented): A method according to claim 11, wherein the
2 incident light is polarized and wherein the polarized incident light is used to distinguish between
3 reflected light on the object and scattered light in the object.